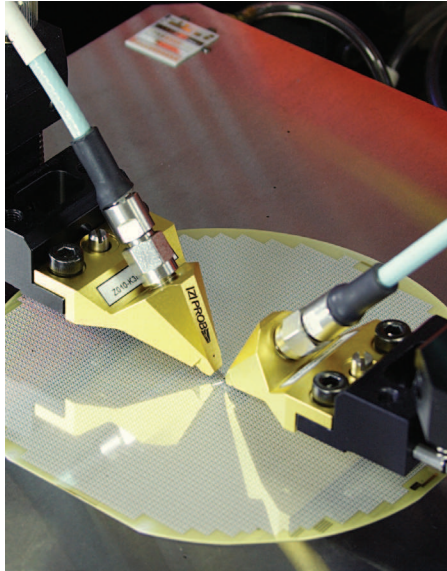


Cascade Microtech, Inc.

SPECIFICATION SHEET



**High-stable HF wafer contact
ideal for automated wafer testing**

|Z|Probe®

High-Frequency Wafer Probe (GS/SG 10 GHz)

A Ground-Signal (GS) configuration is the most cost-effective RF design as less wafer space is taken up with contact pads. Cascade Microtech's |Z| Probe in a GS/SG configuration enables wafer-level testing with the highest accuracy and throughput available while maintaining excellent electrical behavior regardless of footprint size. It is ideal for reliable high-volume production testing, providing proven unsurpassed contact repeatability.

Cascade Microtech's GS/SG |Z| Probes are configured for probing up to 10 GHz making them ideal for testing SAW devices. Long, independent contact springs touch down precisely yet gently even on metal layer thicknesses down to an ultra-thin 50 nm.

The unique |Z| Probe design with its independent spring contacts minimizes the impact between tips and pads. Therefore, by design the |Z| Probe overcomes the limitations of the traditional micro-coax and thin-film style HF probes which typically cause damage after multiple contacts.

The |Z| Probe has an extremely low contact resistance on gold as well as on aluminum pads. The |Z| Probe GS/SG 10 GHz is available from 50 μm to 1250 μm standard pitches. A special left/right version is also available to provide unhindered two-port testing from one side.

FEATURES AND BENEFITS

Durability

- Incredibly long lifetime
- Unparalleled repeatable and reliable contact quality
- Suitable for automated testing

Flexibility

- Probe on most pad material with minimal damage
- Independent, long contact springs easily overcome pad height differences up to 50 μm
- Small structures such as 40 μm x 40 μm pads can be tested
- Excellent performance in vacuum environments and temperatures from 10 K to 300°C

RF performance

- Lowest insertion loss
- High isolation
- Lowest contact resistance

SPECIFICATIONS*

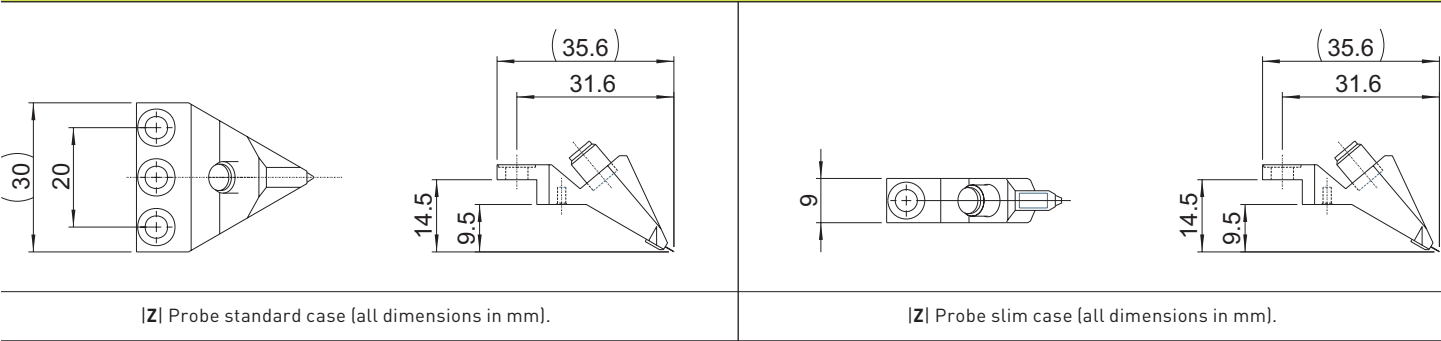
Electrical Characteristics	
Characteristic impedance	50 Ω
Return loss	> 20 dB DC to 10 GHz**
Insertion loss	< 0.6 dB DC to 10 GHz**
Maximum RF power	5 W at 10 GHz
Maximum DC current	1 A
Maximum DC voltage	75 V
Contact resistance on Au	6 mΩ**

Mechanical Characteristics	
Contacts	Solid nickel springs
Insulator	RF dielectric
Contact cycles on Al	> 1,000,000
Contact spring pressure	4 N/mm
Available standard pitches	550 μm to 1250 μm with 50 μm increments***

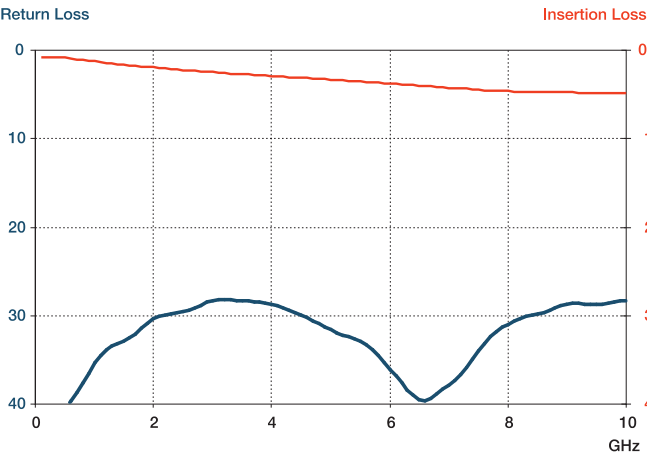
RF Connector	
Type	PC 2.92 mm
Coupling torque	0.8 Nm to 1.1 Nm (Recommended)
Outer contact	Stainless steel
Center contact	CuBe with Au plating
Insulator	PS

*Data, design and specification depend on individual process conditions and can vary according to equipment configurations. Not all specifications may be valid simultaneously.
**Typical for probes with pitches from 100 μm to 200 μm
***100 μm to 500 μm pitch available upon request

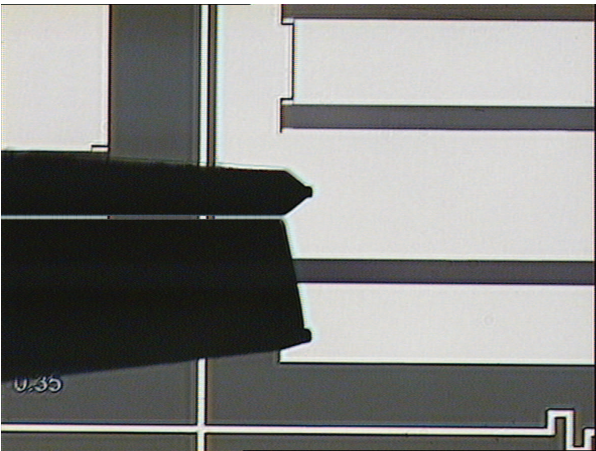
PHYSICAL DIMENSIONS (FOOTPRINT)



APPLICATIONS

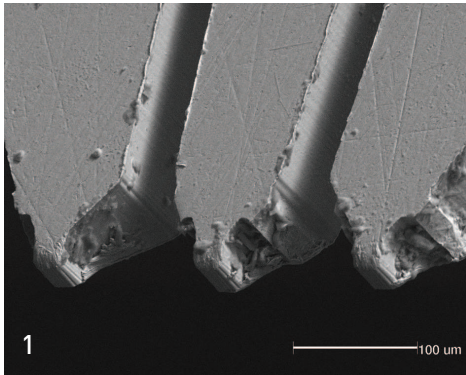


Uncalibrated performance of a |Z| Probe 10 K3N GS 150.

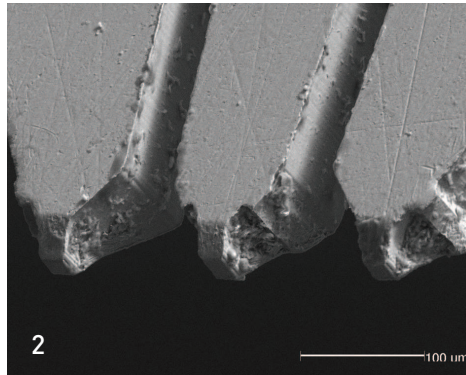


|Z| Probe with 400 μm pitch on a SAW filter structure.

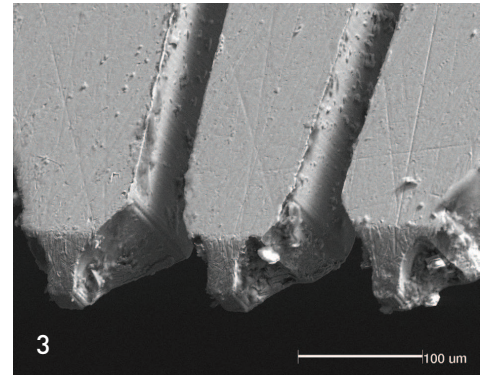
Long lifetime of |Z| Probe (Contact material: Al Overtravel: 75 µm)



New |Z| Probe (upside-down)



The same probe after 1.5 million touchdowns



The same probe after three million touchdowns

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Data subject to change without notice

ZProbe10-ss-0310

Cascade Microtech, Inc.
toll free: +1-800-550-3279
phone: +1-503-601-1000
email: cmi_sales@cmicro.com

Cascade Microtech GmbH
phone: +49-811-60005-0
email: cmg_sales@cmicro.com

Cascade Microtech Japan
phone: +81-3-5615-5150
email: cmj_sales@cmicro.com

Cascade Microtech Shanghai
phone: +86-21-3330-3188
email: cmc_sales@cmicro.com

Cascade Microtech Singapore
phone: +65-6873-7482
email: cms_sales@cmicro.com

Cascade Microtech Taiwan
phone: +886-3-5722810
email: cmt_sales@cmicro.com